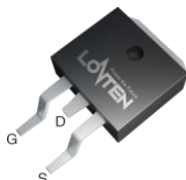
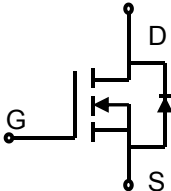


Lonten N-channel 85V, 120A, 3.6mΩ Power MOSFET

Description These N-Channel enhancement mode power field effect transistors are using shielded gate trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and with stand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications. Features ◆ 85V, 120A, $R_{DS(on).max}=3.6m\Omega@V_{GS}=10V$ ◆ Improved dv/dt capability ◆ Fast switching ◆ 100% EAS Guaranteed ◆ Green device available Applications ◆ Motor Drives ◆ UPS ◆ DC-DC Converter ◆ Energy Storage	Product Summary <table> <tr> <td>V_{DSS}</td><td>85V</td></tr> <tr> <td>$R_{DS(on).max}@V_{GS}=10V$</td><td>3.6mΩ</td></tr> <tr> <td>I_D</td><td>120A</td></tr> </table> Pin Configuration  TO-263  N-Channel MOSFET 	V_{DSS}	85V	$R_{DS(on).max}@V_{GS}=10V$	3.6mΩ	I_D	120A
V_{DSS}	85V						
$R_{DS(on).max}@V_{GS}=10V$	3.6mΩ						
I_D	120A						

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	85	V
Continuous drain current ($T_C = 25^\circ\text{C}$) ($T_C = 100^\circ\text{C}$)	I_D	120 100	A
Pulsed drain current ¹⁾	I_{DM}	480	A
Gate-Source voltage	V_{GSS}	± 20	V
Avalanche energy ²⁾	E_{AS}	552	mJ
Power Dissipation	P_D	179	W
Storage Temperature Range	T_{STG}	-55 to +150	$^\circ\text{C}$
Operating Junction Temperature Range	T_J	-55 to +150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.7	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Ambient ³⁾	$R_{\theta JA}$	65	$^\circ\text{C/W}$

Package Marking and Ordering Information

Device	Device Package	Marking	Units/Reel
LSGE085R036	TO-263	LSGE085R036	800

Electrical Characteristics
 $T_J = 25^{\circ}\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV_{DSS}	$V_{GS}=0\text{ V}$, $I_D=250\mu\text{A}$	85	---	---	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	2.2	---	3.8	V
Drain-source leakage current	I_{DSS}	$V_{DS}=85\text{ V}$, $V_{GS}=0\text{ V}$, $T_J = 25^{\circ}\text{C}$	---	---	1	μA
		$V_{DS}=85\text{ V}$, $V_{GS}=0\text{ V}$, $T_J = 150^{\circ}\text{C}$	---	---	10	mA
Gate leakage current, Forward	I_{GSSF}	$V_{GS}=20\text{ V}$, $V_{DS}=0\text{ V}$	---	---	100	nA
Gate leakage current, Reverse	I_{GSSR}	$V_{GS}=-20\text{ V}$, $V_{DS}=0\text{ V}$	---	---	-100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10\text{ V}$, $I_D=50\text{ A}$, $T_J = 25^{\circ}\text{C}$	---	3.1	3.6	m Ω
		$T_J = 150^{\circ}\text{C}$	---	5.8	---	
Forward transconductance	g_{fs}	$V_{DS}=5\text{ V}$, $I_D=100\text{ A}$	---	88	---	S
Dynamic characteristics						
Input capacitance	C_{iss}	$V_{DS} = 42.5\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 250\text{ kHz}$	---	6848	---	pF
Output capacitance	C_{oss}		---	994	---	
Reverse transfer capacitance	C_{rss}		---	26	---	
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 42.5\text{ V}$, $V_{GS}=10\text{ V}$, $I_D = 50\text{ A}$	---	44.4	---	ns
Rise time	t_r		---	114	---	
Turn-off delay time	$t_{d(off)}$		---	340	---	
Fall time	t_f		---	61	---	
Gate resistance	R_g	$V_{GS}=0\text{ V}$, $V_{DS}=0\text{ V}$, $f=1\text{ MHz}$	---	2.2	---	Ω
Gate charge characteristics						
Gate to source charge	Q_{gs}	$V_{DS}=68\text{ V}$, $I_D=50\text{ A}$, $V_{GS}= 10\text{ V}$	---	32	---	nC
Gate to drain charge	Q_{gd}		---	34	---	
Gate charge total	Q_g		---	116	---	
Gate plateau voltage	$V_{plateau}$		---	5	---	V
Output Charge	Q_{oss}	$V_{DS}=68\text{ V}$, $V_{GS}= 0\text{ V}$	---	133	---	nC
Drain-Source diode characteristics and Maximum Ratings						
Continuous Source Current	I_S		---	---	120	A
Pulsed Source Current	I_{SM}		---	---	480	A
Diode Forward Voltage	V_{SD}	$V_{GS}=0\text{ V}$, $I_S=50\text{ A}$, $T_J=25^{\circ}\text{C}$	---	---	1.1	V
Reverse Recovery Time	t_{rr}	$I_S=50\text{ A}$, $di/dt=100\text{ A}/\mu\text{s}$, $T_J=25^{\circ}\text{C}$	---	49	---	ns
Reverse Recovery Charge	Q_{rr}		---	60	---	nC

Notes:

1: Repetitive Rating: Pulse width limited by maximum junction temperature.

2: $V_{DD}=40\text{ V}$, $V_{GS}=10\text{ V}$, $L=0.5\text{ mH}$, $I_{AS}=47\text{ A}$, $R_G=25\Omega$, Starting $T_J=25^{\circ}\text{C}$.

3: The value of R_{thJA} is measured by placing the device in a still air box which is one cubic foot.

Electrical Characteristics Diagrams

Figure 1. Typ. Output Characteristics

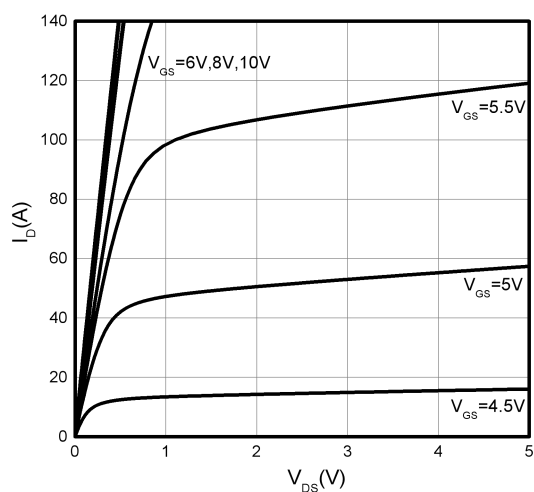


Figure 2. Transfer Characteristics

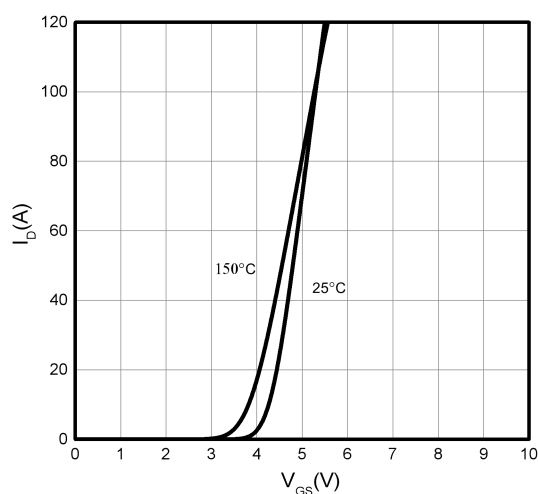


Figure 3. On-Resistance vs. Drain Current

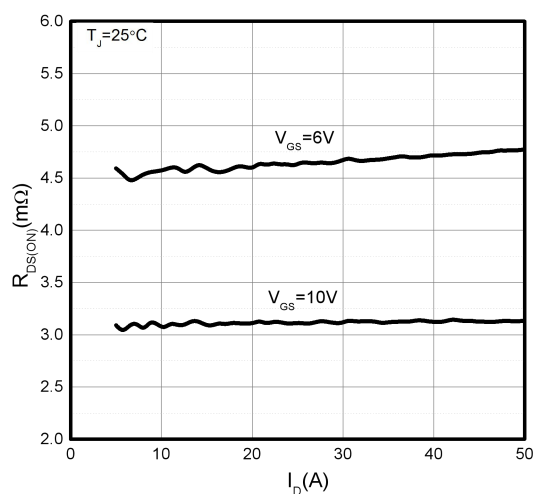


Figure 4. On-Resistance vs. Temperature

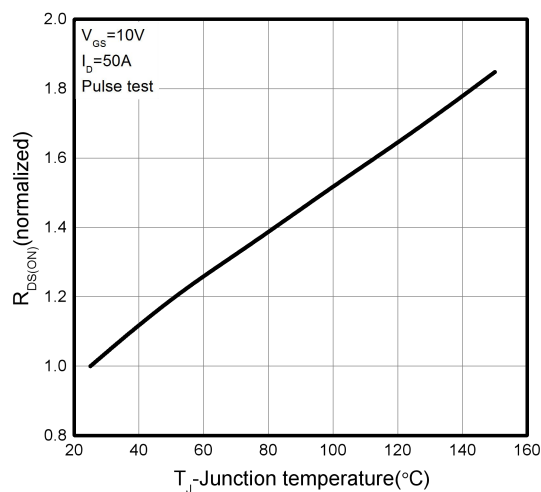


Figure 5. Breakdown Voltage vs. Temperature

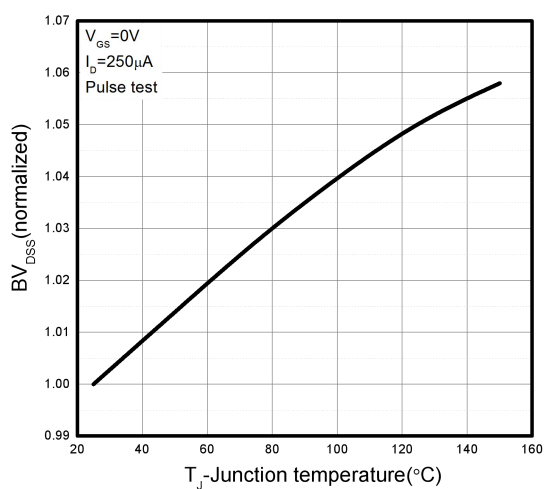


Figure 6. Threshold Voltage vs. Temperature

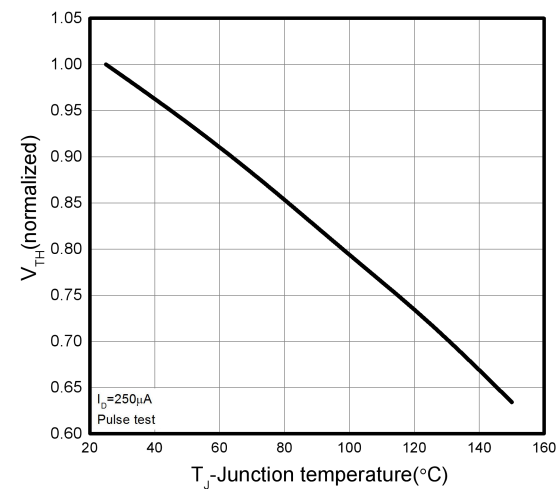


Figure 7. $R_{DS(on)}$ vs. Gate Voltage

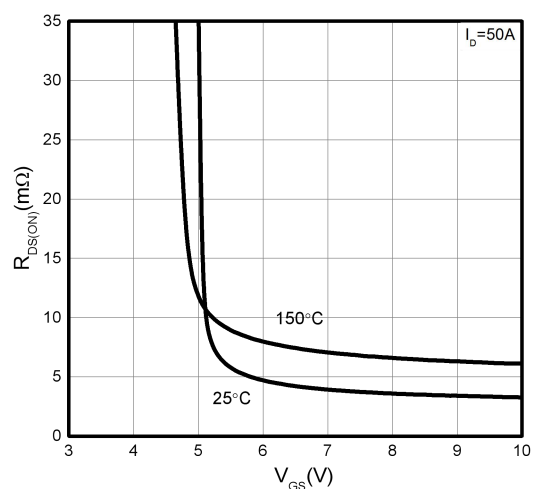


Figure 8. Body-Diode Characteristics

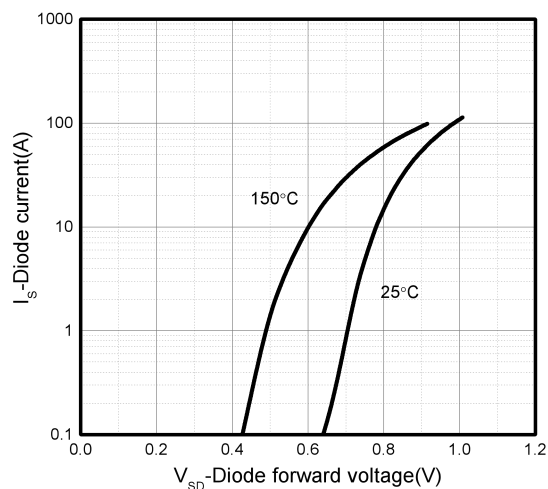


Figure 9. Capacitance Characteristics

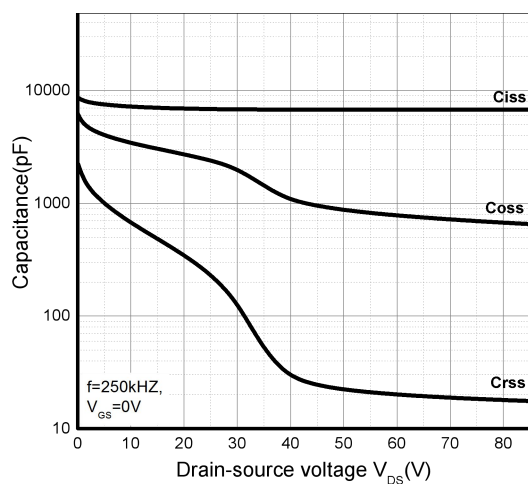


Figure 10. Gate Charge Characteristics

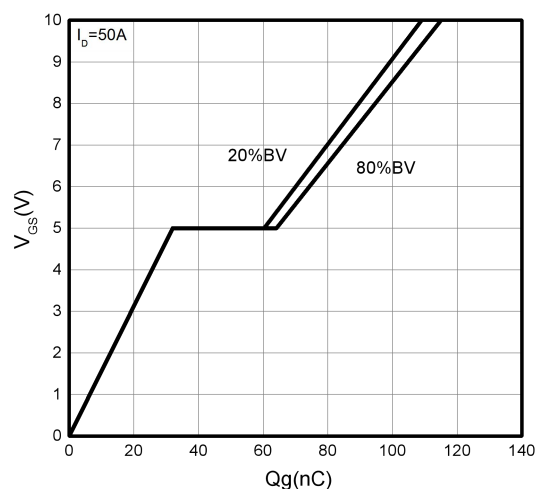


Figure 11. Drain Current Derating

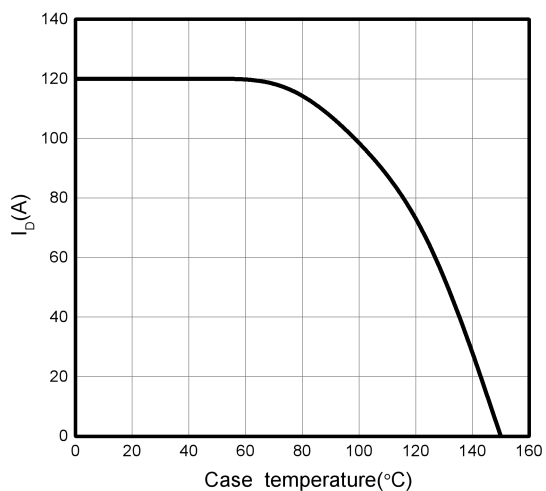


Figure 12. Power Dissipation vs. Temperature

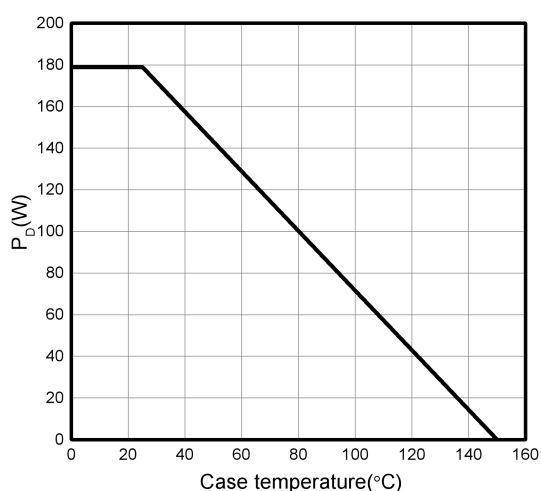


Figure 13: Safe Operating Area

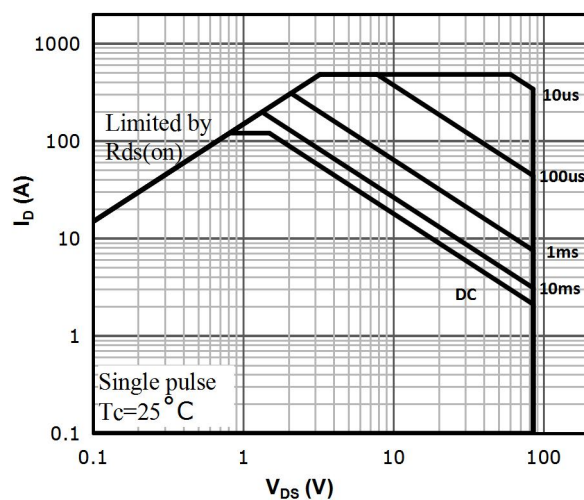
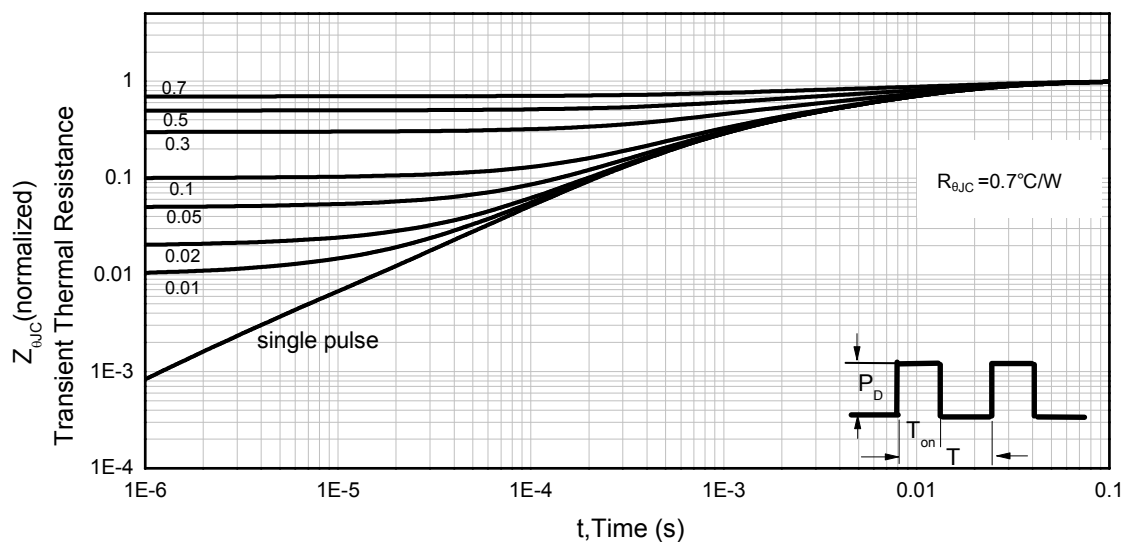
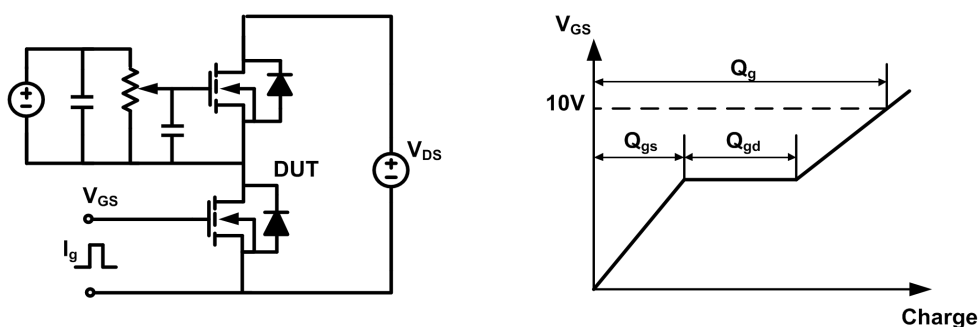


Figure 14. Normalized Maximum Transient Thermal Impedance (R_{thJC})

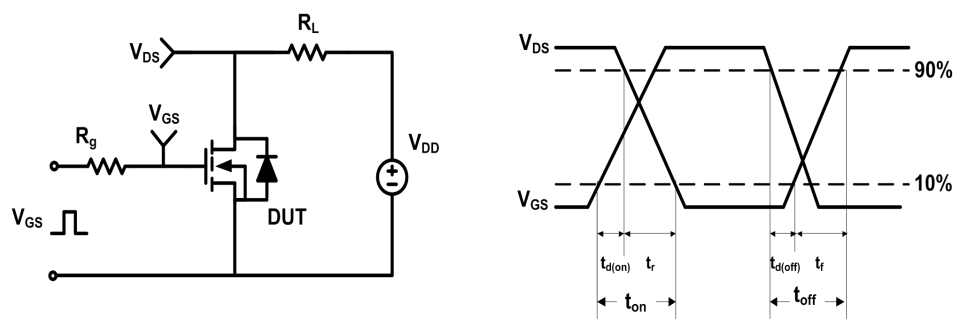


Test Circuit & Waveforms

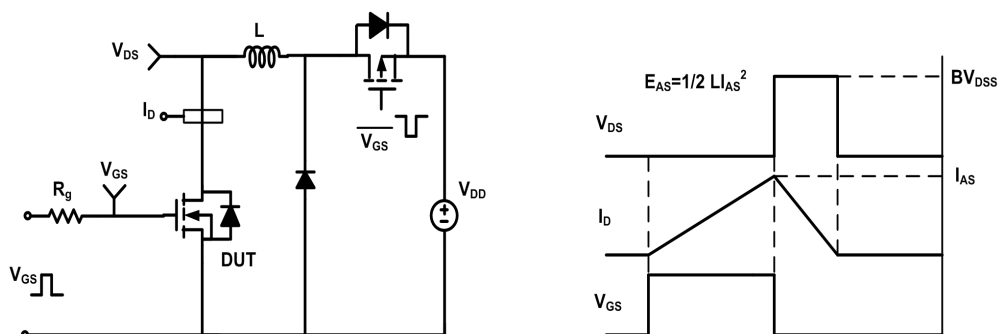
Gate Charge Test Circuit & Waveform



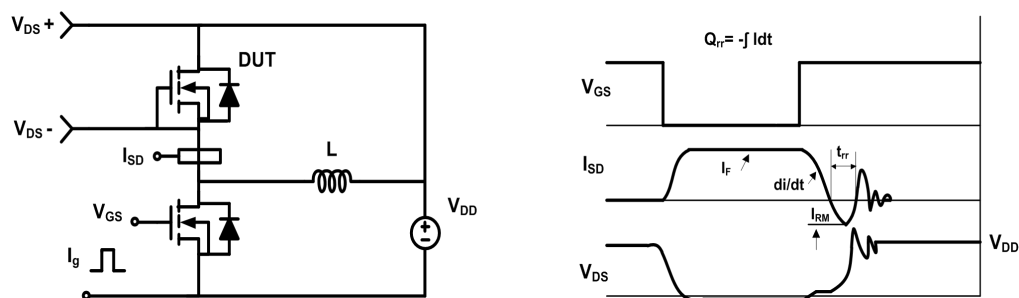
Resistive Switching Test Circuit & Waveform



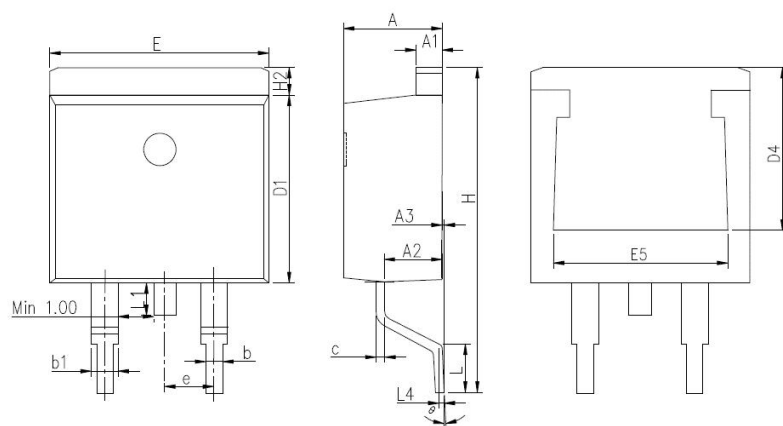
Unclamped Inductive Switching (UIS) Test Circuit & Waveform



Diode Recovery Test Circuit & Waveform



Mechanical Dimensions for TO-263



DIMENSIONS IN MILLIMETERS		
SYMBOL	MIN	MAX
A	4.36	4.8
A1	1.19	1.42
A2	2.2	2.96
A3	0	0.25
b	0.7	0.96
b1	1.17	1.47
c	0.3	0.69
D1	8.5	9.5
D4	6.6	—
E	9.8	10.55
E5	7.06	8.7
e	2.54BSC	
H	14.7	15.7
H2	0.95	1.65
L	1.9	2.8
L1	—	1.78
L4	0.25BSC	
θ	0°	9°

Revision History

LSGE085R036

Revision:2022-04-08 ,Rev 1.0

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